# **2018 IEEE 27th Asian Test** Symposium (ATS 2018)

Hefei, China 15 – 18 October 2018



IEEE Catalog Number: CFP18067-POD **ISBN:** 

978-1-5386-9467-1

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IEEE Catalog Number: ISBN (Print-On-Demand): ISBN (Online): ISSN: CFP18067-POD 978-1-5386-9467-1 978-1-5386-9466-4 1081-7735

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